

Impact of the IBA techniques on the study of cultural heritage materials

The Louvre, palace of the French kings since 1190, became a museum in 1793.

Laboratory location,

underground, in the Louvre garden near the 'Porte des Lions'.



Outline

- How to extract a particle beam to atmosphere
- Ion Beam Analysis
- Evolution of our external beam setup
- Sequential PIXE/RBS with successive beams of protons and alphas:
 - The analysis of lustered ceramics.
- Simultaneous PIXE/RBS with a single shot of α particles:
 - The analysis of a patina.
 - Usewear of tools.
- Some new improvements
- Future prospects
- But before going to IBA I would like to present you a 500 year old lady: Mona Lisa

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Mona Lisa 'la Joconde

visual examination: The whole electromagnetic spectrum as a probe.

- Art historians ; typology of objects

UV : 0,3 – 0,4 μm IR : 0,8 – 2,5 μm X ray Radiography : E_{RX} < 420 keV

- Under-drawings ; 'Pentimento' ; etc

79,4 cm x 53,4 cm x 13 mm; painting on a wooden poplar panel



A 16th century portrait painted in oil on a poplar panel by Leonardo Da Vinci during the Italian Renaissance.

Portrait of Lisa Gherardini, wife of Francesco del Giocondo (1495).

Leonardo took the painting from Italy to France in 1516 when King François I invited the painter to work at the Clos Lucé near the king's castle in Amboise.

After the French Revolution, it was moved to the Louvre. The first time someone described this painting was in 1625. The painting was presented in New York (1963) in Moscow & Tokyo (1974) and came to our lab C2RMF for examination in 2004.

X-ray radiography

 E_{RX} = 45 kV





UV fluorescence photography

Shows the restorations



Infrared photography 900 nm



We start to penetrate inside the paint layer: more details are seen !



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Infrared reflectography 1000 to 2200 nm 'Pentimento' of the painter





Pentimento



Emissiography polychromatic X-ray spectrum $E_{RX} < 290 \text{ kV}$; 4 mA; 2 min



X-ray radiography Versus Emissiography



XRF (X-Ray Fluorescence spectrometry) : Portable X-ray fluorescence spectrometer for elemental analysis



X-ray tube from MOXTEK Silver anode ; 3 W power SDD from Röntec with a resolution of 150 eV

XRF – Mona Lisa pigments:

Lead white (carbonates ?) Copper blue (azurite ?) Copper green (main-hite ?) Yellow of lead and tin Vermillan (cinnabar ?) Black (carbon ?) rown (clays from Umbris: Fe

Due to absorption, below Si there is no XRF signal for low Z elements

Quantitative analysis of Della Robbia glazes with a portable XRFspectrometer and its comparison to PIXE methods. A. Gianoncelli, J. Castaing, A. Bouquillon, A. Polvorinos, P. Walter. X-ray Spectrometry, 2006, vol. 35, pp. 365 - 369

AU CŒUR DE « LA JOCONDE » : Léonard de Vinci décodé. Ouvrage réalisé avec le C2RMF . Édition publiée sous la direction de Michel Menu, Jean-Pierre Mohen et Bruno Mottin, 128 pages, 325 ill. Livres d'Art, Gallimard [2006]



Portable XRD: structural analysis of works of art.



Introduction => IBA

Applications of IBA to cultural heritage mostly rely on the use of **PIXE**:

- high sensitivity down to trace elements
- ease of implementation at atmospheric pressure

However the poor depth information, of this technique, is a strong limitation frequently of primary importance in art works having multilayer structure like paintings, glazed ceramics, patinated bronzes, etc..

RBS can provide detailed depth information, but cannot readily be implemented in air due to potential beam deterioration by energy loss.

We have progressively developed setups that permit to combine PIXE and RBS / NRA under the best conditions with one / or two external beam(s).

Overview of the AGLAE facility



The high voltage generator

NEC machine (pelletron) :6SDH-2 tandem model 2 MV terminal voltage with a turbo pumped gas stripper



A beam of charged particles propagating in air: the external beam

Benefits

- direct analysis of artefacts any shape and any size
- no sampling
- no charging, no preparation
 no heating, reduced damage
 easy sample positioning
- 120-mm air path for 3-MeV p
 thin exit foil



Detail of the extraction snout





3 MeV proton µ-beam extracted to helium atmosphere through a silicon nitride membrane Memb. area: 1 mm2 Memb. thickness: 100 nm

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Ion Beam Analysis

MeV ion beam based techniques constitute a powerful tool for the quantitative determination of the composition and structure of matter



Possibility of mapping with a spatial resolution of ~ 10 um



PIXE in art and archeology

PIXE is applied to the study of provenance and / or fabrication technique for major, minor and trace element analysis (field of application)





BABYLONE du 14 mars au 2 juin 2008

> Flash version

> Html version

Adjunction of SB detector: A set-up able to perform RBS (proton / alpha) in atmosphere

SB detector under vacuum In a small housing Solid angle adjustable With Si_3N_4 membrane as entrance wi Positioning XYZ stage Fixed angle at 150°

Pumping

Ol

20



Combined PIXE-RBS protons and/or alphas (old version)

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Sequential PIXE/RBS with successive beams of protons and alpha particles:

The analysis of lustered ceramics.

Experiments on ceramics

Study of lustered ceramics from Seville. *A. Polverinos (University Seville, Spain).* Lustered sherds from a Triana workshop, 15th century.



Study of materials and techniques of lustered majolicas. *G. Padeletti (ISMN-CNR, Italy)*. *Lustre from Gubbio, Italy*, Mastro Giorgio 16th century.



Combination of PIXE (3 MeV p) and RBS (3 MeV He ions) to measure composition and thickness of glaze and lustre



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What is lustre ?

- Decoration on top of the glaze with a metallic aspect
- It can have different colours
- It is made of a layer of metallic (Cu, Ag) nano particles

Lustre layer of Cu or Ag nano particles Glaze (SnO₂ = opacity pigments) Ceramic body

"metal salts mixed with a paste of clay are applied on top of a glazed object – the pottery is then fired again in a reducing atmosphere"



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-Presence of Cu and some Ag responsible for red lustre.

8-oct-08

Thickness evaluation from alpha RBS Spectra (Italy)



	0	Na	AI	Si	Κ	Ca	Cu	Ag	Pb	Thickness	
	at%	at%	at%	at%	at%	at%	at%	at%	at%	10 ¹⁵ at/cm?	nm
1. Layer	62.0	1.7	1.5	30.1	3.3	0.6	0.0	0.0	0.5	550	77
Luster	54.8	0.0	0.0	19.4	3.0	0.6	5.0	13.0	4.2	650	92
Glaze (PIXE)	62.0	1.7	1.5	25.1	3.3	0.6	0.0	0.0	5.5	inf.	inf.



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RBS Lustre layer models:





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Metallic reflection from the surface layer; light back-scattered from tin-opacified glaze.



From Kingery W.D. and Vandiver P.B. 1986

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Main conclusions on lustres

RBS provides the detailed description of the sub-surface region.

>RBS is a non destructif methode.

Detailed structre of lustre is related to its origine

Lustre effect is produced by a thin glaze (100-200 nm) layer containing Cu and Ag.

Lustre layer from Spain is thinner and simpler than Italian one.

Both technologies (Spain / Italy) seem to depart from original Islamic technology .



Simultaneous PIXE/RBS with a single shot of 3 MeV α particles:

Usewear of tools.

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Usewear on stone tools: traceology

- A discipline used to determine the function of stone tools. Our study concerns flint, which was the material of choice of prehistoric man.

- If the tool is used for a relatively long period, a significant layer of residue can build up on the knife edge.

- Analysis of this layer can thus reveal the presence of elements that can identify the worked material. Thus, the presence of calcium and phosphorus indicates that the tool was used on animal material such as bone or horn.





Analysis of the knife edge using alpha PIXE at 3 MeV





3 Mev alpha μ-beam (D=12 μm), was well adapted to the quantification of light elements ...

Flint without and with polish.

Bone components (Ca and P) are found on the edge of the knife used for cutting bones.



RBS analysis of the knife edge.



RBS spectrum of a tool with and without polish. The tool was used to work fresh bone during 30 mn. The simulation gives a 400 nm thick layer composed of 80% of apatite and 20% of calcium carbonate.



RBS profile on a knife edge



-Lateral scan of a bone polish. (The sample was scanned in steps of 500 µm with a 3 MeV alpha beam)
-We also measured the carbon profile on the knife edge using the nuclear reaction 12C(d,p)13C.
-The analysis of Egyptian Predynastic ceremonial knives showed that they have been used to cut plants like cereals ...



Simultaneous PIXE/RBS with a single shot of 6 MeV α particles:

The analysis of a patina.

Combined PIXE / RBS on the patina of a drop dispenser

Japanese, shakudo decorated, drop dispenser (19 century) first known black bronzes (patina): Egypt 2500 BC first Japanese Shakudo (patina): 14 century



Due to their well adapted range, 6 MeV α particles are used to simultaneously profile (RBS) and quantify (PIXE) the artificial patina.





Combined PIXE / RBS on the patina of a drop dispenser





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Diffraction diagram of the shakudo patina

Cu₂O is red but the presence in this oxide of some Au and or Ag (solution or nano crystals) changes the color to black ! => signature of a shakudo.





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Technical improvements





Technical details





8-oct-0



Combined PIXE-RBS protons and/or alphas



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Conclusion and prospects

-The development of a sophisticated external beam setup has permitted to implement simultaneously or sequentially PIXE(PIGE) and RBS.

-The setup is currently under improvement to permit simultaneous NRA measurement (depth profiles of light elements via d or 3He induced nuclear reactions) in addition to PIXE and RBS (by using a sectorised annular detector).

- 3He PIXE should even be more advantageous than 4He PIXE.

-The coupling of these techniques provides a wealth of information on cultural heritage objects, not easily attainable with any other single method.

-Although XRF (specially on synchrotron radiation facilities) can be subsituted to PIXE for trace element analysis, PIXE (and thus the whole set of IBA techniques) remains attractive because it can be complemented by PIGE for the measurements of light elements in the bulk material and RBS+NRA for depth profiling.

Thank you for your attention ...